Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	•
10/768,501	INOUE ET AL.	
Examiner	Art Unit	
David E. Bochna	3679	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
285	319	1/30/2006	
	93		

SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
Updated the previous search	1/30/2006	DB
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